Abstracts

Sensitivity analysis of calibration standards for fixed probe spacing on-wafer calibration techniques [vector network analyzers]

A.M.E. Safwat and L. Hayden. "Sensitivity analysis of calibration standards for fixed probe spacing on-wafer calibration techniques [vector network analyzers]." 2002 MTT-S International Microwave Symposium Digest 02.3 (2002 Vol. III [MWSYM]): 2257-2260 vol.3.

In vector network analyzer calibration, it is clear that the uncertainty in the standard definition leads to inaccurate measurement. We investigate the sensitivity of different on-wafer calibration techniques to probe positioning. Calibration comparison derived error-bounds are calculated for various cases differing only by a single change in probe/standard overlap.

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